

**Notice of References Cited**

Application/Control No.

10/511,862

Applicant(s)/Patent Under  
Reexamination  
WASHAKOWSKI ET AL.

Examiner

Leon-Viet Q. Nguyen

Art Unit

2635

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**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-4,737,969 A	04-1988	Steel et al.	375/298
*	B	US-5,212,714 A	05-1993	Grindahl et al.	375/216
*	C	US-5,519,732 A	05-1996	Chester, David B.	375/295
*	D	US-5,648,988 A	07-1997	Iwamatsu et al.	375/232
*	E	US-6,031,431 A	02-2000	Vinekar, Sanjay R.	332/103
*	E	US-6,144,862 A	11-2000	Oliver et al.	455/550.1
*	G	US-6,263,027 B1	07-2001	Yang et al.	375/302
*	H	US-2001/0055331 A1	12-2001	Agazzi et al.	375/216
*	I	US-2002/0075092 A1	06-2002	Turcotte et al.	332/100
*	J	US-2003/0002570 A1	01-2003	Chan, Kevin T.	375/216
*	K	US-2004/0141569 A1	07-2004	Agazzi, Oscar E.	375/302
*	L	US-6,879,642 B2	04-2005	Taskinen, Kimmo	375/302
*	M	US-7,046,970 B2	05-2006	Nguyen et al.	455/110

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
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**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
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	X	

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**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-4,682,123 A	07-1987	Loper et al.	332/100
*	B	US-5,440,506 A	08-1995	Longway et al.	365/104
*	C	US-5,523,726 A	06-1996	Kroeger et al.	332/103
*	D	US-5,570,392 A	10-1996	Young et al.	375/308
*	E	US-5,757,794 A	05-1998	Young, William Ronald	370/362
*	F	US-6,075,813 A	06-2000	Chen et al.	375/216
*	G	US-6,175,599 B1	01-2001	Lyon et al.	375/261
*	H	US-2002/0018600 A1	02-2002	LYON et al.	382/305
*	I	US-2002/0049797 A1	04-2002	Temerinac, Miodrag	708/319
*	J	US-2002/0141440 A1	10-2002	Stanley et al.	370/465
*	K	US-6,560,296 B1	05-2003	Glas et al.	375/308
*	L	US-2005/0201481 A1	09-2005	Calderbank et al.	375/265
*	M	US-6,985,492 B1	01-2006	Thi et al.	370/429

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
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**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-5,392,299 A	02-1995	Rhines et al.	714/756
*	B	US-6,536,005 B1	03-2003	Augarten, Michael H.	714/723
*	C	US-2003/0142764 A1	07-2003	Keevill et al.	375/341
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
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